

# <span id="page-0-0"></span>**BTN7030-1EPA**

# **NovalithIC™ Lite – smart integrated half-bridge**

# **Features**

- Low-side and high-side switch in half-bridge configuration with diagnosis and embedded protection
- Part of NovalithIC™ family
- Switch ON capability while inverse current condition (InverseON)
- Green product (RoHS compliant)

### **Protection features**

- Temperature limitation with intelligent latch
- Overcurrent protection (tripping) with intelligent latch for both the low-side and high-side output stage
- Undervoltage shutdown
- Cross current protection

### **Diagnostic features**

- Proportional load current sense for high-side load currents
- Open load in ON and OFF state
- Short circuit to ground or battery

# **Potential applications**

- Replaces electromechanical relays, fuses and discrete circuits
- Suitable for driving motors and solenoids of a max. inductance of 3 mH at maximal current
- Temperature dependent overload detection current level with min. 17 A (T」 < 75°C), min. 15 A (T」 = 125°C) and min. 14 A (T<sub>J</sub> = 150°C)
- Current sense diagnosis optimized for motor and solenoid applications



#### **Figure 1 Potential application**







Datasheet Please read the Important Notice and Warnings at the end of this document 1.2 **[www.infineon.com](https://www.infineon.com)** Downloaded From **[Oneyac.com](https://www.oneyac.com)** 



### <span id="page-1-0"></span>**Description**

# **Description**

The BTN7030-1EPA is a protected half-bridge with integrated driver, providing protection and diagnosis functions. The device is integrated in SMART7 technology.

#### **Table 1 Product Summary**



# **Product validation**

Qualified for automotive applications. Product validation according to AEC-Q100.



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<span id="page-4-0"></span>**Block diagram and terms**





#### **Figure 2**

## **1.1 Terms**

**Figure 3** shows all terms used in this data sheet, with associated convention for positive values.





**Figure 3 Voltage and current convention**



### <span id="page-5-0"></span>**Pin configuration**

# **2 Pin configuration**



**Figure 4 Pin configuration**

## **2.1 Pin definitions and functions**



1) All output pins of the channel must be connected together on the PCB. All pins of the output are internally connected together. PCB traces have to be designed to withstand the maximum current which can flow.



<span id="page-6-0"></span>**Absolute maximum ratings**

# **3 Absolute maximum ratings**

## **3.1 Absolute maximum ratings**

#### **Table 3 Absolute maximum ratings**

 $T_J$  = -40°C to +150°C; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified); all voltages with respect to ground, positive current flowing into pin (unless otherwise specified) Not subject to production test - specified by design.





#### <span id="page-7-0"></span>**Absolute maximum ratings**

#### **Table 3 (continued) Absolute maximum ratings**

 $T$ <sub>J</sub> = -40°C to +150°C; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified); all voltages with respect to ground, positive current flowing into pin (unless otherwise specified) Not subject to production test - specified by design.



1) Maximum  $V_{\text{DI}}$  to be considered for latch-up tests: 5.5 V<br>2) ESD susceptibility. HBM according to ANSI/ESDA/JEDE

2) ESD susceptibility, HBM according to ANSI/ESDA/JEDEC JS001 (1.5 kΩ, 100 pF)

3) ESD susceptibility, Charged Device Model "CDM" according JEDEC JESD22-C101

- Stresses above the ones listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.
- Integrated protection functions are designed to prevent IC destruction under fault conditions described in the data sheet. Fault conditions are considered as "outside" normal operating range. Protection functions are not designed for continuous repetitive operation.

## **3.2 Functional range**

#### **Table 4 Functional range**

Not subject to production test - specified by design.



1) Protection functions still operative

2) In case of  $V_S$  voltage decreasing:  $V_{S(EXT,LOW),MIN} = 3.5$  V. In case of  $V_S$  voltage increasing:  $V_{S(EXT,LOW),MIN} = 3.8$  V

Note: Within the functional or operating range, the IC operates as described in the circuit description. The electrical characteristics are specified within the conditions given in the Electrical Characteristics table.

## **3.3 Thermal resistance**

This thermal data was generated in accordance with JEDEC JESD51 standards. For more information, go to **[www.jedec.org](http://www.jedec.org)**.



#### **Absolute maximum ratings**

#### **Table 5 Thermal resistance**

Not subject to production test - specified by design.



1) According to Jedec JESD51-2,-5,-7 at natural convection on FR4 2s2p board; the Product (Chip + Package) was simulated on a 76.2 × 114.3 × 1.5 mm board with two inner copper layers (2 × 70 µm Cu, 2 × 35 µm Cu). Where applicable a thermal via array under the exposed pad contacted the first inner copper layer. Simulation done at  $T_{\text{AMB}} = 105^{\circ}$ C and  $P_{\text{dissination}} = 1$  W.



**Figure 5 Typical thermal impedance for Tambient = 85°C; Simulation with 1 W of power dissipation**



#### <span id="page-9-0"></span>**Logic pins**

# **4 Logic pins**

The device has 3 digital pins for direct control of the device.

The logic thresholds for "low" and "high" states are defined by parameters  $V_{DI(TH)}$  and  $V_{DI(HYS)}$ . The relationship between these two values is shown in *Figure 6*. The voltage  $V_{\text{IN}}$  needed to ensure an "high" state is always higher than the voltage needed to ensure a "low" state. The digital input pins are compatible with 3.3 V and 5 V micro-controllers.



## **4.1 Input pin (IN)**

The input pin IN activates either the low-side or the high-side output stage, in case the enable pin EN is set to "high" and no fault is present.

## **4.2 Enable pin (EN)**

The Enable (EN) pin activates the device. When EN pin is set to "high", the device is in Active mode. When it is set to "low", the device goes into Sleep mode, with the output stage set to tri-state (low-side and high-side switches are set OFF). The protection latch is cleared by a "low" signal with a minimum length of  $t_{DE|AV(T,R)}$  at the EN pin.

## **4.3 Diagnosis Enable pin (DEN)**

The Diagnosis Enable (DEN) pin controls the diagnosis circuitry and the protection circuitry. When DEN pin is set to "high", the diagnosis is enabled (see **[Chapter 8.2](#page-31-0)** for more details). When it is set to "low", the diagnosis is disabled (IS pin is set to high impedance).

The transition from "high" to "low" of DEN pin clears the protection latch of the channel depending on the logic state of EN pin and DEN pulse length (see **[Chapter 7.3](#page-25-0)** for more details).



#### <span id="page-10-0"></span>**Logic pins**

# **4.4 Electrical characteristics logic pins**

#### **Table 6 Electrical characteristics logic pins**

 $V_S$  = 6 V to 18 V,  $T_J$  = -40°C to +150°C; Typical values:  $V_S$  = 13.5 V,  $T_J$  = 25°C; Digital Input (DI) pins = IN, DEN, EN; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)





#### <span id="page-11-0"></span>**Power supply**

## **5 Power supply**

The BTN7030-1EPA is supplied by  $V_S$ , which is used for the internal logic as well as supply for the power output stage.  $V_S$  has an undervoltage detection circuit, which prevents the activation of the power output stage and diagnosis in case the applied voltage is below the undervoltage threshold.

## **5.1 Operation modes**

BTN7030-1EPA has three operation modes, with the transition between the operation modes is determined according to these variables:

- logic level at EN pin
- logic level at DEN pin

The state diagram including the operation modes and the possible transitions is shown in **Figure 7**. The behavior of BTN7030-1EPA as well as some parameters may change in dependence from the operation mode of the device. Furthermore, due to the undervoltage detection circuitry which monitors  $V_s$  supply voltage, some changes within the same operation mode can be seen accordingly. In case of a fault, the BTN7030-1EPA will not go into sleep mode, unitl the latch is cleared.



**Figure 7 Operation mode state diagram**

## **5.1.1 Unsupplied**

In this state, the device is either unsupplied (no voltage applied to VS pin) or the supply voltage is below the undervoltage threshold.

#### **5.1.2 Power-up**

The Power-up condition is entered when the supply voltage  $(V_S)$  is applied to the device. The supply is rising until it is above the undervoltage threshold  $V_{S(OP)}$  therefore the internal power-on signals are set.

## **5.1.3 Sleep mode**

The device is in Sleep mode when all Digital Input pins (IN, DEN, EN) are set to "low". When BTN7030-1EPA is in Sleep mode, both high-side and low-side power stages are OFF. The current consumption is minimum (see



#### <span id="page-12-0"></span>**Power supply**

parameter I<sub>VS(SLEEP)\_85\_stdy</sub>). No Overtemperature or Overload protection mechanism is active when the device is in Sleep mode, only the InverseON protection for the low-side power output stage is active (see **[Chapter 6.3.1](#page-16-0)** for further details). In case of activation, the current consumption of the device is increased.The device can go in Sleep mode only if the protection is not active (latch = 0, see **[Chapter 7.3.1](#page-25-0)** for further details).

## **5.1.4 Stand-by mode**

The device is in Stand-by mode as long as DEN pin is set to "high" while the EN pin is set to "low". Both the high-side and low-side power stages are OFF, therefore only Open Load in OFF diagnosis is possible. Depending on the load condition, either a fault current /<sub>IS(FAULT)</sub> or an Open Load in OFF current /<sub>IS(OLOFF)</sub> may be present at IS pin. In such a situation, the current consumption of the device is increased.

## **5.2 Undervoltage on VS**

Between  $V_{S(OP)}$  and  $V_{S(UV)}$  the undervoltage mechanism is triggered. If the device is operative (in Active mode) and the supply voltage drops below the undervoltage threshold  $V_{S(1)}$ , the internal logic switches OFF the output channel.

As soon as the supply voltage  $V_S$  is above the operative threshold  $V_{S(DP)}$ , the channel is switched ON again with a hysteresis of  $V_{S(HYS)}$ .

## **5.3 Electrical characteristics power supply**

#### **Table 7 Electrical characteristics power supply**

 $V_{\mathsf{S}}$  = 6 V to 18 V,  $T_{\mathsf{J}}$  = -40°C to +150°C; Typical values:  $V_{\mathsf{S}}$  = 13.5 V,  $T_{\mathsf{J}}$  = 25°C

Typical resistive load connected to the output for testing (unless otherwise specified):  $R_{load} = 3.3 \Omega$ all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)





#### <span id="page-13-0"></span>**Power supply**

#### **Table 7 (continued) Electrical characteristics power supply**

 $V_{\mathsf{S}}$  = 6 V to 18 V,  $T_{\mathsf{J}}$  = -40°C to +150°C; Typical values:  $V_{\mathsf{S}}$  = 13.5 V,  $T_{\mathsf{J}}$  = 25°C Typical resistive load connected to the output for testing (unless otherwise specified):  $R_{load} = 3.3 \Omega$ all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)



1) Not subject to production test - specified by design



#### <span id="page-14-0"></span>**Power stages**

## **6 Power stages**

The high-side power stage is built using a N-channel vertical Power MOSFET with charge pump, while the low-side power stage uses no charge pump.

## **6.1 Output ON-state resistance**

The ON-state resistance  $R_\mathsf{DS(ON)}$  depends mainly on junction temperature T<sub>J</sub>. **Figure 8** shows the variation of  $R_{\rm DS(ON)}$  across the whole  $T_{\rm J}$  range. The value "2" on the y-axis corresponds to the maximum  $R_{\rm DS(ON)}$  measured at  $T_J = 150^{\circ}$ C.



Figure 8 Typical R<sub>DS(ON)</sub> vs. junction temperature for low-side and high-side output stage

## **6.2 Switching loads**

## **6.2.1 Switching times**

When switching resistive loads, the switching times and slew rates shown in **[Figure 9](#page-15-0)** and **[Figure 10](#page-15-0)** can be considered. The switch energy values  $E_{ON(xS)}$  and  $E_{OFF(xS)}$  are proportional to the load resistance and times  $t_{ON(xS)}$  and  $t_{OFF(xS)}$ .



#### <span id="page-15-0"></span>**Power stages**





**Figure 9 Switching a resistive load to ground (high-side), for EN="high"**





## **6.2.2 Output voltage limitation**

To increase the current sense accuracy of the high-side output stage,  $V_{DS}$  voltage is monitored.



#### <span id="page-16-0"></span>**Power stages**

When the output current /<sub>L</sub> decreases while the channel is diagnosed (DEN pin set to "high" - see <mark>Figure 11</mark>) bringing  $V_{DS}$  equal or lower than  $V_{DS(SLC)(HS)}$ , the output DMOS gate is partially discharged. This increases the output resistance so that  $V_{DS} = V_{DS(SLC)(HS)}$  even for very small output currents.



#### **Figure 11 Output voltage limitation activation during diagnosis, with EN="high"**

The  $V_{DS}$  increase allows the current sensing circuitry to work more efficiently, providing better  $k_{\text{ILIS}}$  accuracy for output current in the low range.

## **6.3 Advanced switching characteristics**

## **6.3.1 Inverse current behavior for the high-side switch**

When V<sub>OUT</sub> > V<sub>S</sub>, a current /<sub>INV</sub> flows into the high-side power output transistor (see **[Figure 12](#page-17-0)**). Similar for V<sub>OUT</sub> < GND (0 V), a current /<sub>INV</sub> flows into the low-side power output transistor. This condition is known as "Inverse Current".

If the channel is in OFF- state, the current flows through the intrinsic body diode generating high power losses therefore an increase of overall device temperature. If the channel is in ON- state,  $R_{DS(1)N}$  can be expected and power dissipation in the output stage is comparable to normal operation in  $R_{DS(ON)}$ .

With InverseON, it is possible to switch ON or OFF the high-side power output channel during inverse current condition.



#### <span id="page-17-0"></span>**Power stages**



#### **Figure 12 Inverse current circuitry for low-side and high-side**

## **6.3.2 Inverse current behavior for the low-side switch**

With InverseON, the low-side power output channel is activated under all operational conditions for  $V_{OUT}$  <  $V_{\text{INV}(LS)}$ , also in case of any fault to protect the low-side power output transistor.

The circuitry is active in any operational condition, fault condition, stand-by or sleep mode.

The power supply consumption for voltage monitoring, without activation of the power output stage, is included in **[Table 7](#page-12-0)**. In case of activation of the low-side power output stage, when switched on by the protection circuitry, an operating supply current of  $I_{V\{S(\vert NVON\rangle(\vert S)\vert\}}$  is required during activation.

When  $V_{OUT}$  is small again, the low-side output-stage is switched according to the EN and IN pin.

Note: No protection mechanism like Overtemperature or Overload protection is active during applied Inverse Currents for both low-side and high-side output transistor.

## **6.4 Electrical characteristics power stages**

#### **Table 8 Electrical characteristics power stages switching**

 $T_J$  = -40°C to +150°C;  $R_{load}$  = 3.3 Ω, single pulse,

all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)





#### **Power stages**

#### **Table 8 (continued) Electrical characteristics power stages switching**

 $T_{\sf J}$  = -40°C to +150°C;  $R_{\sf load}$  = 3.3 Ω, single pulse,

all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)





#### **Power stages**

#### **Table 8 (continued) Electrical characteristics power stages switching**

 $T_{\sf J}$  = -40°C to +150°C;  $R_{\sf load}$  = 3.3 Ω, single pulse,

all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)



#### **Table 9 Electrical characteristics - power output stages**

 $V_S$  = 6 V to 18 V,  $T_J$  = -40°C to +150°C; Typical values:  $V_S$  = 13.5 V,  $T_J$  = 25°C

Typical resistive load connected to the output for testing (unless otherwise specified):  $R_{load} = 3.3 \Omega$ all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)



#### **12 mΩ high-side**

#### **Output characteristics**



#### **Switching energy**



#### **Power stages**

#### **Table 9 (continued) Electrical characteristics - power output stages**

 $V_{\mathsf{S}}$  = 6 V to 18 V,  $T_{\mathsf{J}}$  = -40°C to +150°C; Typical values:  $V_{\mathsf{S}}$  = 13.5 V,  $T_{\mathsf{J}}$  = 25°C Typical resistive load connected to the output for testing (unless otherwise specified):  $R_{load} = 3.3 \Omega$ all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)



## **Switching energy**



#### <span id="page-21-0"></span>**Power stages**

#### **Table 9 (continued) Electrical characteristics - power output stages**

 $V_{\mathsf{S}}$  = 6 V to 18 V,  $T_{\mathsf{J}}$  = -40°C to +150°C; Typical values:  $V_{\mathsf{S}}$  = 13.5 V,  $T_{\mathsf{J}}$  = 25°C Typical resistive load connected to the output for testing (unless otherwise specified):  $R_{load} = 3.3 \Omega$ all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)



1) Not subject to production test - specified by design



#### <span id="page-22-0"></span>**Protection**

## **7 Protection**

The BTN7030-1EPA is protected against overtemperature, overload and overvoltage.

Overtemperature and overload protections are working when the device is not in sleep mode.

Overvoltage protection works in all operation modes.

## **7.1 Overtemperature protection**

An increase of the junction temperature  $\tau_{\text{\tiny J}}$  above the thresholds  $\tau_{\text{\tiny J(SD)}}$  switches OFF both the high-side and low-side output stages to prevent destruction. The channel remains switched OFF until the temperature has reached the "Restart" condition described in **[Table 10](#page-25-0)**. The behavior is shown in **Figure 13**. From protection point of view, pins IN and EN are equivalent.



**Figure 13 Overtemperature protection, with EN = "high" and load to GND**

When the overtemperature protection circuitry allows the channel to be switched ON again, the Intelligent latch strategy described in **[Chapter 7.3.1](#page-25-0)** is followed.



#### <span id="page-23-0"></span>**Protection**

## **7.2 Overload protection**

The BTN7030-1EPA is protected in case of overload, short circuit to battery (low-side output stage) or short circuit to ground (high-side output stage). For the high-side output stage, two overload thresholds are defined (see **Figure 14**) and selected automatically depending on the voltage  $V_{DS}$  across the power DMOS:

Overload current thresholds variation with  $V_{DS}$  for the high-side output stage

- $I_{L(OVL0)}$  when  $V_{DS}$  < 13 V
- $I_{L(OVL1)}$  when  $V_{DS}$  > 22 V





In order to allow a higher load inrush at low ambient temperature, the overload threshold for the high-side output stage is maximum at low temperature and decreases when  $\tau_{\text{\tiny J}}$  increases (see **[Figure 15](#page-24-0)**).

For the high-side output stage,  $I_{1(OM 0)}$  typical value remains constant up to a junction temperature of +75°C.



#### <span id="page-24-0"></span>**Protection**



#### **Figure 15 Overload current thresholds variation with T<sup>J</sup>**

The power supply voltage  $V_S$  can increase above 18 V for short time, for instance in load dump or in jump start condition. Whenever  $V_S \geq V_{S(JS)}$ , the overload detection current for the high-side output stage is set to IL(OVL\_JS)(HS) as shown in **Figure 16**.



Figure 16 Overload detection current variation with  $V_S$  voltage for the high-side output stage



#### <span id="page-25-0"></span>**Protection**

When /<sub>L</sub> ≥ /<sub>L(OVL)</sub> (either /<sub>L(OVL0)</sub> or /<sub>L(OVL1)</sub>, in either the low-side or high-side output stages) the output stage is switched OFF (both low-side and high-side). The output stage is allowed to be reactivated according to the strategy described in **Chapter 7.3**.

## **7.3 Protection and diagnosis in case of fault**

Any event that triggers a protection mechanism (either Overtemperature or Overload) has consequences:

- the output stage switches OFF and the internal latch is set to "1"
- if the diagnosis is active for the channel, a current I IS(FAULT) is provided by IS pin (see **[Chapter 8.2.2](#page-33-0)** for further details)

If all the "restart" conditions described in **Table 10** are fullfilled, the latch can be reset, thus the output stage can be switched ON again.

Furthermore, the device has the intelligent latch to protect itself against unwanted repetitive restart in fault condition.





## **7.3.1 Intelligent latch strategy (INTLAT)**

When EN is set to "high", the channel is switched ON. In case of fault condition the output stage latches OFF. There are two ways to de-latch the switch.

With EN pin:

It is necessary to set the pin to "low" for a time longer than  $t_{\text{DELAY(LR)}}$  ("latch reset delay" time) to de-latch the channel. This is independent from the state of the IN pin. The channel can be allowed to restart only if the "restart" conditions for the protection mechanisms are fulfilled (see **Table 10**).

During the "latch reset delay" time, if the pin is set to "high" the channel remains switched OFF and the timer  $t_{\text{DELAY(LR)}}$  is reset and it is not started as long as the pin remains at "high". It restarts as soon as the pin is set to "low" again.

The intelligent latch strategy is shown in **[Figure 17](#page-26-0)**.

With DEN pin:

It is possible to "force" a reset of the internal latch without waiting for  $t_{\text{DELAY(LR)}}$  by applying a pulse (rising edge followed by a falling edge) to the DEN pin while EN pin is "low". The pulse applied to DEN pin must have a duration longer than  $t_{\text{DEN(LR)}}$  to ensure a reset of the internal latch.

The timing is shown in **[Figure 18](#page-26-0)**.



### <span id="page-26-0"></span>**Protection**









**Figure 18 Intelligent latch timing diagram with forced reset, with IN = "high" and load to GND** 



#### <span id="page-27-0"></span>**Protection**

## **7.4 Additional protections**

## **7.4.1 Overvoltage protection**

The clamping structure limits the negative / positive output voltage so that  $V_{DS(xS)} = V_{DS(CLAMP)}$ , for both the high-side and low-side output stage. The clamping structure protects the device in all operative modes listed in Chapter **[Chapter 6.1](#page-14-0)**.

In the case of supply voltages between  $V_{S(FXTUP)}$  and  $V_{BAT(ID)}$ , the output transistor is still operational and follows the input pin.

In addition, there is a clamp mechanism available for Overvoltage protection for the logic and the output channel, monitoring the voltage between VS and GND pins ( $V_{S(CLAMP)}$ ).



#### **Figure 19 Output clamp concept**

## **7.4.2 Cross current protection**

In half-bridge applications it has to be assured that the high-side and low-side power output stages are not conducting at the same time, connecting directly the battery voltage to GND. This is assured by a circuit in the driver logic, generating a so called dead time between switching off one power output stages and switching on the other. This is ensured by monitoring the state of the MOSFETs.

## **7.5 Electrical characteristics protection**



### **Protection**

#### **Table 11 Electrical characteristics protection**

 $V_S$  = 6 V to 18 V,  $T_J$  = -40°C to +150°C; typical values:  $V_S$ = 13.5 V,  $T_J$  = 25 °C; typical resistive load connected to the output for testing (unless otherwise specified):  $R_{load} = 3.3$  Ω





### <span id="page-29-0"></span>**Protection**

#### **Table 11 (continued) Electrical characteristics protection**

 $V_S$  = 6 V to 18 V,  $T_J$  = -40°C to +150°C; typical values:  $V_S$ = 13.5 V,  $T_J$  = 25 °C; typical resistive load connected to the output for testing (unless otherwise specified):  $R_{load} = 3.3$  Ω



#### **Protection power output stage - 20 mΩ low-side**



1) Functional test only

2) Tested at  $T_{\text{J}}$  = 150°C only

3) Not subject to production test - specified by design



# <span id="page-30-0"></span>**8 Diagnosis**

For diagnosis purpose, the BTN7030-1EPA provides a combination of digital and analog signals at pin IS. These signals are generically named SENSE and written /<sub>IS</sub>. In case of disabled diagnostic, IS pin becomes high impedance.

A sense resistor  $R_{\text{SENSE}}$  must be connected between IS pin and module ground if the current sense diagnosis is used. A typical value is  $R_{\text{SENSF}} = 1.2 \text{ k}\Omega$ .

Due to the internal connection between IS pin and  $V_S$  supply voltage, it is not recommended to connect the IS pin to the sense current output of other devices, if they are supplied by a different battery feed.

## **8.1 Overview**

**Table 12** gives a quick reference for the state of the IS pin during BTN7030-1EPA operation.

<b>Inputs</b>			<b>Outputs</b>			<b>Diagnostic Output</b>
<b>EN</b>	IN	<b>DEN</b>	<b>HSS</b>	<b>LSS</b>	OUT $(V_{\text{OUT}})$	(IS)
$\mathbf 0$	Χ	1	<b>OFF</b>	<b>OFF</b>	3)	Z
						$I_{\text{IS}(\text{FAULT})}$ if latch $\neq 0$
			<b>OFF</b>	<b>OFF</b>	$V_S - V_{DS(OLOFF)}$	Z
					$V_S - V_{DS(OLOFF)}$	I <sub>IS</sub> (OLOFF)
						$I_{IS(FAULT)}$ if latch $\neq 0$
			<b>OFF</b>	ON	$\sim$ $V_{\text{INV}}$ = $V_{\text{OUT}}$ <	Z
						$I_{IS(FAULT)}$ if latch $\neq 0$
			<b>OFF</b>	<b>OFF</b>	$\sim$ $V_{\text{INV}}$ = $V_{\text{OUT}}$ > $V_{\text{S}}$	I <sub>IS</sub> (OLOFF)
						$I_{\text{IS}(\text{FAULT})}$ if latch $\neq 0$
1	0		<b>OFF</b>	ON	$~\sim$ GND	$Z = I_{\text{IS(OFF)}}$
	$\mathbf{1}$		ON	<b>OFF</b>	$\sim V_{\rm S}$	$I_{15} = I_L / k_{1L15}$ (> $I_{15(EN)}$ )
	X		<b>OFF</b>	<b>OFF</b>	3)	I <sub>IS(FAULT)</sub>
	X		<b>OFF</b>	<b>OFF</b>	$~\sim$ GND	I <sub>IS(FAULT)</sub>
	0		<b>OFF</b>	<b>OFF</b>	$\sim V_{\rm S}$	I <sub>IS(FAULT)</sub>
	1				$\sim V_{\rm S}$	Z
					$~\sim$ GND	I <sub>IS(FAULT)</sub>
	$\mathbf{1}$		ON	<b>OFF</b>	$\sim V_{S}^{-1}$	$I_{\text{IS(EN)}}$
	1		ON	<b>OFF</b>	$\sim V_{S}^{2}$	$I_{\text{IS(EN)}} < I_{\text{IS}} < I_{\text{L(NOM)}}$ / $k_{\text{ILIS}}$
	Χ		<b>OFF</b>	<b>OFF</b>	Z	$I_{IS(FAULT)}$
	$\mathbf{1}$		ON	<b>OFF</b>	$V_{\text{OUT}}$ > $V_{\text{S}}$	$I_{\text{IS(EN)}}$
Χ	Χ	Χ	<b>OFF</b>	ON	$\sim$ $V_{\text{INV}}$ = $V_{\text{OUT}}$ < $V_{INV(LS)}$	
Χ	Χ	X	<b>OFF</b>	<b>OFF</b>	$\overline{a}$	$\mathsf Z$
0	$\mathbf 0$	$\mathbf 0$	<b>OFF</b>	<b>OFF</b>	Z	$\mathsf Z$
Χ	Χ	0			3)	$\mathsf Z$
						$V_{INV(LS)}$

**Table 12 SENSE signal, function of application condition**



- <span id="page-31-0"></span>1) The output current has to be lower than  $I_{L(OL)}$
- 2) The output current has to be higher than  $I_{L(OL)}$
- 3) load dependent

### **Table 13 Signal value explanation**





- **Figure 20 Simplified State Diagram for DEN = "high" (unless otherwise specified)**
- Grey arrow: Transition caused by change of environmental conditions.
- Black arrow: Possible transition by digital input pins (EN, DEN or IN pin).

## **8.2 Diagnosis in ON state**

A current proportional to the load current through the high-side output stage (ratio  $k_{\sf ILIS}$  = / $_{\sf L}$  / /<sub>IS</sub>) is provided at pin IS when the following conditions are fulfilled:



#### <span id="page-32-0"></span>**Diagnosis**

- the power output stage is switched ON with  $V_{DS}$  < 2 V
- the diagnosis is enabled
- no fault (as described in **[Chapter 7.3](#page-25-0)**) is present or was present and not cleared yet (see **[Chapter 8.2.2](#page-33-0)** for further details)

If a "hard" failure mode is present or was present and not cleared yet a current /<sub>IS(FAULT)</sub> is provided at IS pin.

## **8.2.1** Current sense  $(k_{\text{HIS}})$

The accuracy of the sense current depends on temperature and load current.  $I_{\sf IS}$  increases linearly with  $I_{\sf L}$  output current through the high-side switch until  $l_\mathsf{L}$  reaches the overload detection current  $l_{\mathsf{L}(\mathsf{OVL}x)}$ . In case of open load at the output stage (I<sub>L</sub> close to 0 A), the maximum sense current I<sub>IS(EN)</sub> (no load, diagnosis enabled) is specified. This condition is shown in **[Figure 21](#page-33-0)**. The blue line represents the ideal  $k_{\text{ILIS}}$  line, while the red lines show the behavior of a typical product.

An external RC filter between IS pin and microcontroller ADC input pin is recommended to reduce signal ripple and oscillations (a minimum time constant of  $1 \mu s$  for the RC filter is recommended).

The  $k_{\text{HIS}}$  factor is specified with limits that take into account effects due to temperature, supply voltage and manufacturing process. Tighter limits are possible (within a defined current window) with calibration:

• a well-defined and precise current ( $I_{L(CAL)}$ ) is applied at the output during end of line test at customer side

• the corresponding current at IS pin is measured and the  $k_{\text{HIS}}$  is calculated ( $k_{\text{HIS}} \textcircled{ d}_{\text{L(CAI)}}$ )

• within the current range going from  $I_{L(CA)}$ <sub>LO</sub> to  $I_{L(CA)}$ <sub>H</sub> the  $k_{HIS}$  is equal to  $k_{HIS} \otimes I_{L(CA)}$  with limits defined by  $Δk<sub>IIIS</sub>$ 

The derating of kILIS after calibration is calculated using the formulas in **Current sense ΔkILIS calculation formulas** and it is specified by  $\Delta k_{\text{HIS}}$ 

#### **Current sense ΔkILIS calculation formulas**

$$
\Delta k_{ILIS, MIN} = 100 * MIN \left( \frac{k_{ILIS} @ I_{L(CAL)} L}{k_{ILIS} @ I_{L(CAL)}} - 1, \frac{k_{ILIS} @ I_{L(CAL)} H}{k_{ILIS} @ I_{L(CAL)}} - 1 \right)
$$

#### **Equation 1**

$$
\Delta k_{ILIS,MAX} = 100 * MAX\left(\frac{k_{ILIS} \mathcal{Q}^{I}L(CAL)}{k_{ILIS} \mathcal{Q}^{I}L(CAL)} - 1, \frac{k_{ILIS} \mathcal{Q}^{I}L(CAL)H}{k_{ILIS} \mathcal{Q}^{I}L(CAL)} - 1\right)
$$

#### **Equation 2**



#### <span id="page-33-0"></span>**Diagnosis**



#### **Figure 21 Current sense ratio in open load at ON condition**

The calibration is intended to be performed at  $T_{A(CAL)} = 25^{\circ}$ C. The parameter  $\Delta k_{ILIS}$  includes the drift over temperature as well as the drift over the current range from  $I_{L(CAL)}$  L to  $I_{L(CAL)}$  H.

## **8.2.2 Fault current (***I***<sub>IS(FAULT)</sub>**

As soon as a protection event occurs, the value of the internal latch (see **[Chapter 7.3](#page-25-0)** for more details) is changed from 0 to 1, a current /<sub>IS(FAULT)</sub> is provided by pin IS when DEN is set to "high"and both the high-side and low-side output stage of the affected channel are switched OFF.

If the device is switched OFF by protection event and its EN pin is driven by PWM with pulse width  $\lt t_{\text{DELAY(LR)}}$ , the internal latch could not be reset, the current /<sub>IS(FAULT)</sub> is provided each time the device diagnosis is activated by DEN.

If the device is OFF and the internal latch is not in the reset state, the current / $_{\sf IS(FAULT)}$  is also provided each time the device diagnosis is checked.

**[Figure 22](#page-34-0)** shows the relation between high-side current sense (I<sub>IS</sub> = I<sub>L</sub> /  $k_{\text{ILIS}}$ ) and I<sub>IS(FAULT)</sub>.



#### <span id="page-34-0"></span>**Diagnosis**



#### **Figure 22 SENSE behavior - overview**

If present (EN = IN = DEN = 1, no fault present), the current sense signal can be differentiated from the fault current  $I_{\text{IS}(\text{FAULT})}$ , up to the max. possible load current  $I_{\text{L}(\text{OVLO})_2}$ -40(HS), max.

## **8.3 Diagnosis in OFF state**

When a power output stage is in OFF state, the BTN7030-1EPA can measure the output voltage and compare it with a threshold voltage. In this way, using some additional external components (a pull-down resistor and a switchable pull-up current source) it is possible to detect if the load is missing or if there is a short circuit to battery. If a fault condition was detected by the device (the internal latch has a value different from the reset value, as described in **[Chapter 8.2.2](#page-33-0)**) a current /<sub>IS(FAULT)</sub> is provided by IS pin each time the channel diagnosis is checked also in OFF state.

## 8.3.1 Open load current ( $I_{\text{IS(OLOFF)}}$ )

In OFF state, when DEN pin is set to "high", the  $V_{DS}$  voltage of the high-side switch is compared with a threshold voltage  $V_{DS(O1 \text{ OFF})}$ . If the load is properly connected and there is no short circuit to battery,  $V_{DS(HS)} \sim V_S$  therefore  $V_{DS(HS)} > V_{DS(OLOFF)}$ . When the diagnosis is active and  $V_{DS(HS)} \leq V_{DS(OLOFF)}$ , a current /<sub>IS(OLOFF)</sub> is provided by IS pin. Open Load in OFF detection is only possible for half-bridge configuration where the load is supposed to be connected between the OUT pin of the device and GND. **[Figure 23](#page-35-0)** shows the relationship between /<sub>IS(OLOFF)</sub> and /<sub>IS(FAULT)</sub> as functions of V<sub>DS</sub>. The two currents don´t overlap making always possible to differentiate between open load in OFF and fault condition.



#### <span id="page-35-0"></span>**Diagnosis**



#### **Figure 23 I<sub>IS</sub>** in OFF State

It is necessary to wait a time  $t_{\sf IS(OLOFF)\_}$  between the falling edge of the pin EN and the sensing at pin IS for open load in OFF diagnosis to allow the internal comparator to settle. In **Figure 24** the timings for an open load detection are shown - the load is always disconnected.







#### <span id="page-36-0"></span>**Diagnosis**

## **8.4 SENSE timings**

**Figure 25** shows the timing during settling  $t_{slS(ON)}$  and disabling  $t_{slS(OFF)}$  of the SENSE (including the case of load change). As a proper signal cannot be established before the load current is stable (therefore before  $t_{ON}$ ):

 $t_{\text{SIS(DIAG)}} = t_{\text{SIS(ON)}} + t_{\text{ON}}$ 







**Figure 26 SENSE Timing with Small Load Current, with EN = "high" and load to GND**



# <span id="page-37-0"></span>**8.5 Electrical characteristics diagnosis**

#### **Table 14 Electrical characteristics diagnosis**

 $V_{\mathsf{S}}$  = 6 V to 18 V,  $T_{\mathsf{J}}$  = -40°C to +150°C; Typical values:  $V_{\mathsf{S}}$  = 13.5 V,  $T_{\mathsf{J}}$  = 25°C Typical resistive load connected to the output for testing (unless otherwise specified): R<sub>load</sub> = 3.3  $\Omega$ all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)





#### **Table 14 (continued) Electrical characteristics diagnosis**

 $V_{\mathsf{S}}$  = 6 V to 18 V,  $T_{\mathsf{J}}$  = -40°C to +150°C; Typical values:  $V_{\mathsf{S}}$  = 13.5 V,  $T_{\mathsf{J}}$  = 25°C Typical resistive load connected to the output for testing (unless otherwise specified):  $R_{load} = 3.3 \Omega$ all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)







#### <span id="page-39-0"></span>**Table 14 (continued) Electrical characteristics diagnosis**

 $V_{\mathsf{S}}$  = 6 V to 18 V,  $T_{\mathsf{J}}$  = -40°C to +150°C; Typical values:  $V_{\mathsf{S}}$  = 13.5 V,  $T_{\mathsf{J}}$  = 25°C Typical resistive load connected to the output for testing (unless otherwise specified):  $R_{load} = 3.3 \Omega$ all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)



1) Not subject to production test - specified by design<br>2) Tested at  $T_J = 150^{\circ}\text{C}$ 

2) Tested at  $T_{\sf J}$  = 150°C



#### <span id="page-40-0"></span>**Application information**

# **9 Application information**

Note: The following information is given as a hint for the implementation of the device only and shall not be regarded as a description or warranty of a certain functionality, condition or quality of the device.

# **9.1 Application setup**



**Figure 27 BTN7030-1EPA application diagram**

Note: This is a very simplified example of an application circuit. The function must be verified in the real application.

## **9.2 External components**

#### **Table 15 Suggested component values**



**(table continues...)** Datasheet 41 1.2



#### <span id="page-41-0"></span>**Application information**



The stray inductances have to be minimized in the power bridge design as it is necessary in all switched high power bridges. Therefore it is recommended to ensure that the offset between the BTN7030-1EPA's ground (GND pin) and the microcontroller's (signal) ground is minimized.

It is recommended to do the freewheeling in the high-side path until the load current is 0, to avoid reverse currents through the low-side power stage, thus minimizing power dissipation and avoid an unnecessary stress of the device.

If used in full bridge configuration, it is strongly recommended to change the direction of a motor not before the motor fully stopped thus motor current is 0 A, in order to avoid overvoltage at OUT due to back EMF, e.g. in load dump situations.

If the load also can provide power to the device, e.g. a motor or inductance in generator mode, it is recommended not to use only a diode for reverse polarity but to allow a current flow back to the supply  $V_{\text{bat}}$ , to prevent the device from overvoltage situations. In such a scenario, the capacitor  $C_{\text{VS}}$  between VS and GND pin has to be dimensioned accordingly.

Note: The suggested component values above are determined for typical applications. Based on the application circuit and the used components connected to BTN7030-1EPA, it could be necessary to adjust the values above to stay below the maximum ratings for all components. (e.g. reverse battery, transients on battery, ...)

## **9.3 Bidirectional loads and open load in OFF detection**

A bidirectional load, like a motor or a solenoid, can be driven with two BTN7030-1EPA half-bridge in H-bridge configuration, as shown in **[Figure 28](#page-42-0)**.

In order to perform an open load in OFF detection, the high-side output stage of one half-bridge has to be switched on with IN = EN = "high" (right BTN7030-1EPA in **[Figure 28](#page-42-0)**). As described in **[Chapter 8.3.1](#page-34-0)**, and in combination with a pull-up resistor  $R_{\text{PL}}$  (or alternatively a pull-down resistor  $R_{\text{PD}}$ ) the other half-bridge can check for open load condition.



## <span id="page-42-0"></span>**Application information**



### **Figure 28 Application circuit: H-bridge with two BTN7030-1EPA**

#### **Note**

This is a very simplified example of an application circuit. The function must be verified in the real application.

## **9.4 Further application information**

- Please contact us for information regarding the Pin FMEA
- For further information you may contact **http://www.infineon.com/**



#### <span id="page-43-0"></span>**Package dimensions**

**10 Package dimensions**



**Figure 29 PG-TSDSO-14 (thin (slim) dual small outline 14 pins) package outline**



### <span id="page-44-0"></span>**References**



#### **Figure 30 PG-TSDSO-14 (thin (slim) dual small outline 14 pins) package pads and stencil**

To meet the world-wide customer requirements for environmentally friendly products and to be compliant with government regulations the device is available as a green product. Green products are RoHS-Compliant (i.e Pb-free finish on leads and suitable for Pb-free soldering according to IPC/JEDEC J-STD-020).

# **11 References**

# **Revision history**



#### <span id="page-45-0"></span>**Trademarks**

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